



RADIO TEST REPORT

Test Report No. : 29IE0011-HO-01-C

Applicant : FUJITSU FRONTECH LIMITED

Type of Equipment : B-PAD

Model No. : FWT33E2WR

FCC ID : XGP-BPAD06

**Test regulation : FCC Part 15 Subpart C 2009
Section 15.207, Section 15.247**

Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test:

April 27 to June 2, 2009

Tested by:

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EMC Services

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Approved by :

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MF060b (09.01.08)

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SECTION 1: Customer information

Company Name : FUJITSU FRONTECH LIMITED
Address : 1776 Yanokuchi, Inagi-shi, Tokyo 206-8555, Japan
Telephone Number : +81-42-377-0646
Facsimile Number : +81-42-378-9765
Contact Person : Hiroki Kishimoto

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : B-PAD
Model No. : FWT33E2WR
Serial No. : Refer to Clause 4.2
Rating : AC100 - 240V, DC3.7V (Battery)
Receipt Date of Sample : April 18, 2009
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: FWT33E2WR (referred to as the EUT in this report) is the B-PAD. The EUT contains IEEE802.11b/g Wireless LAN and Bluetooth modules. Those modules do not transmit simultaneously. This EUT has variant models, IPAD100-xx and FWT3xxxxR. 'xx', 'xxxx' is described by '0-9', 'A-Z' which is distinguished by country of destination, adapting to PCI v1.3 or not. And here is no influence in the product property.

General Specification

Clock frequencies of the EUT are as follows;

CPU	520MHz, 13MHz, 125MHz, 32.768kHz
3.5 inch TFT color transmissive LCD (320x240 pixel), LED back light, touch panel	6.25MHz
Built in numeric keypad	4.033355MHz
Audio Codec	24.576MHz
CF Card	48MHz
Integrated Magnetic Card Reader	4.915MHz
IEEE802.11b/g Wireless LAN Module	40MHz
Bluetooth Module	16MHz, 32.768kHz

Radio Specification

IEEE802.11b/g Wireless LAN		
Frequency band	Lower limit	2412MHz
	Upper limit	2462MHz
Type of Modulation		DSSS, OFDM
Antenna Type		$\lambda/4$ dielectric chip antenna
Antenna Connector Type		W. FL
Antenna Gain		1.8dBi
ITU code		G1D(DSSS), D1D(OFDM)
Power Supply (Inner)		DC 3.3V

* For IEEE802.11b/g Wireless LAN module test, please see UL Japan Test Report No. 29IE0011-HO-01-A.

Bluetooth		
Frequency band	Lower limit	2402MHz
	Upper limit	2480MHz
Bandwidth & Channel spacing		1MHz & 1MHz / CH
Type of Modulation		FHSS
Antenna Type		$\lambda/4$ dielectric chip antenna
Antenna Connector Type		U. FL
Antenna Gain		-4.3dBi
ITU code		F1D
Power Supply (Inner)		DC 3.3V

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2009, final revised on February 27, 2009

Title : FCC 47CFR Part15 Radio Frequency Devices Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

* The EUT complies with FCC Part 15 Subpart B: 2009, final revised on February 27, 2009.

3.2 Procedures and results

[FHSS]

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst Margin	Results
1	Conducted emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements	FCC: Section 15.207	Conducted	N/A	[Tx] QP 18.1dB 0.19280MHz, L AV 16.7dB 0.45763MHz, L [Rx] QP 19.3dB 0.19290MHz, N AV 17.7dB 0.19290MHz, N	Complied
		IC: RSS-Gen 7.2.2	IC: RSS-Gen 7.2.2				
2	Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)	Conducted	N/A	See data.	Complied
		IC: -	IC: RSS-210 A8.1 (b)				
3	20dB Bandwidth	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)	Conducted	N/A	N/A	Complied
		IC: -	IC: RSS-210 A8.1 (a)				
4	Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)(iii)	Conducted	N/A	N/A	Complied
		IC: -	IC: RSS-210 A8.1 (d)				
5	Dwell time	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(a)(1)(iii)	Conducted	N/A	N/A	Complied
		IC: -	IC: RSS-210 A8.1 (d)				
6	Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(b)(1)	Conducted	N/A	N/A	Complied
		IC: RSS-Gen 4.8	IC: RSS-210 A8.4 (2)				
7	Band Edge Compliance	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(d)	Conducted	N/A	N/A	Complied
		IC: -	IC: RSS-210 A8.5				
8	Spurious Emission	FCC: FCC Public Notice DA 00-705	FCC: Section 15.247(d)	Conducted/ Radiated	N/A	[Tx] 4.3dB 4960.0MHz, AV, Vertical [Rx] 7.0dB 287.522MHz, QP, Horizontal	Complied
		IC: RSS-Gen 4.9 RSS-Gen 4.10	IC: RSS-210 A8.5 RSS-Gen 7.2.1 and 7.2.3				

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

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3.3 Addition to standard

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied Band Width	RSS-Gen 4.6.1	RSS-Gen 4.6.1	Radiated	N/A	N/A	N/A

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (\pm dB)	
	150kHz-30MHz	
No.1	3.7dB	
No.2	3.7dB	
No.3	3.7dB	
No.4	3.7dB	

Test room (semi-anechoic chamber)	Radiated emission (10m*)(\pm dB)			Radiated emission (3m*)(\pm dB)					
	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	1GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz
No.1	3.1dB	4.4dB	3.9dB	3.2dB	3.8dB	3.9dB	5.0dB	5.0dB	5.4dB
No.2	-	-	-	3.2dB	4.4dB	4.0dB	5.0dB	5.2dB	5.4dB
No.3	-	-	-	3.2dB	4.2dB	3.8dB	5.0dB	5.3dB	5.3dB
No.4	-	-	-	3.2dB	4.0dB	3.8dB	5.0dB	5.3dB	5.3dB

*10m/3m = Measurement distance

Power meter (\pm dB)	
Below 1GHz	Above 1GHz
1.0dB	1.0dB

Antenna terminal conducted emission and Power density (\pm dB)			Antenna terminal conducted emission (\pm dB)		Channel power (\pm dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.(Tx/Rx)

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin. (Rx)

The data listed in this report meets the limits unless the uncertainty is taken into consideration. (Tx)

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9
 Receiving (Rx)
 Inquiry

*The details of Operating Mode(s)

Test Item	Mode	Tested frequency
Conducted Emission, Spurious Emission (Conducted/Radiated)	Tx (Hopping off) DH5 Rx	2402MHz 2441MHz 2480MHz 2441MHz
Carrier Frequency Separation	Tx (Hopping on) DH5 Inquiry	2402MHz 2441MHz 2480MHz
20dB Bandwidth	Tx (Hopping off) DH5 Inquiry	2402MHz 2441MHz 2480MHz
Number of Hopping Frequency	Tx (Hopping on) DH5 Inquiry	-
Dwell time	Tx (Hopping on), -DH1, DH3, DH5 Inquiry	-
Maximum Peak Output Power	Tx (Hopping off) DH5 Inquiry	2402MHz 2441MHz 2480MHz
Band Edge Compliance (Conducted)	Tx DH5 -Hopping on -Hopping off	2402MHz 2480MHz
99% Occupied Bandwidth	Tx DH5 -Hopping on -Hopping off	2402MHz 2441MHz 2480MHz
*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)		

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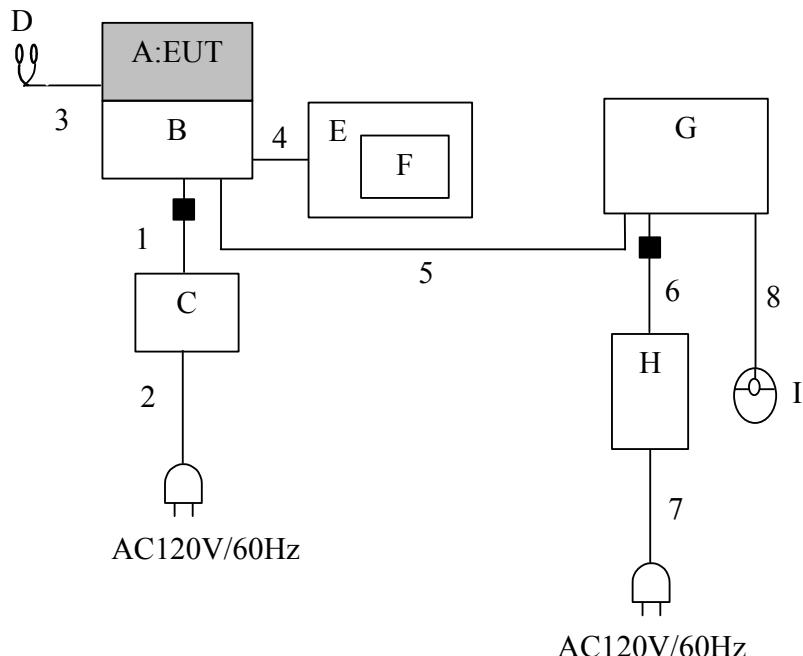
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4.2 Configuration and peripherals

<For Conducted emission test>



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT and support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	B-PAD	FWT33E2WR	4	FUJITSU FRONTECH LIMITED	EUT
B	Cradle	-	-	FUJITSU FRONTECH LIMITED	-
C	AC Adapter	CP360060-01	08601940A	FUJITSU LIMITED.	-
D	Earphone & Microphone	ATT-75	-	audio-technica.	-
E	Battery Charger	FWTCA31R	-	FUJITSU LIMITED.	-
F	Li-ion Battery	CA50601-1000	-	FUJITSU LIMITED.	-
G	PC	T23 (=2647-LJ3)	97-ALT9W	IBM	-
H	AC Adapter	02K6757	11S02K6750Z1Z2UP3561HY	IBM	-
I	Mouse	M-SAS51	LZB92663446	Logitech	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	1.2	Unshielded	Unshielded	Standard Ferrite Core x 1
2	AC Cable	1.9	Unshielded	Unshielded	-
3	Signal Cable	1.1	Shielded	Shielded	-
4	DC Cable	0.15	Unshielded	Unshielded	-
5	USB Cable	1.8	Shielded	Shielded	-
6	DC Cable	1.7	Unshielded	Unshielded	Standard Ferrite Core x 1
7	AC Cable	1.9	Unshielded	Unshielded	-
8	Signal Cable	1.8	Shielded	Shielded	-

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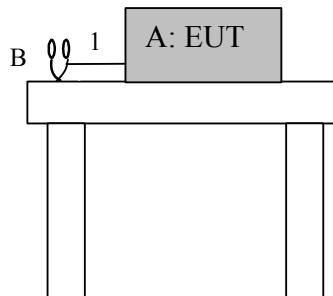
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<For Radiated emission test>



*The test without Cradle had a worst noise level, so that the test was performed with above setup (without connecting USB cable).

*Setup(s) was taken into consideration and test data was taken under worse case conditions.

Description of EUT and support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	B-PAD	FWT33E2WR	4	FUJITSU FRONTECH LIMITED	EUT
B	Earphone & Microphone	ATT-75	-	audio-technica.	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	Signal Cable	1.1	Shielded	Shielded	-

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

1) For the tests on EUT with other peripherals (as a whole system)

I/O cable and AC cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber. The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector	: QP and AV
Measurement range	: 0.15-30MHz
Test data	: APPENDIX
Test result	: Pass

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SECTION 6: Radiated Spurious Emission

Test Procedure

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength intensity has been measured in a Semi Anechoic Chamber with a ground plane and at a distance of 3m(Below 10GHz) and 1m(Upper 10GHz).

The height of the measuring varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 2 of RSS-210 2.7 (IC) and outside the restricted band of FCC15.205 / Table 1 of RSS-210 2.7 (IC).

Frequency	Below 1GHz	Above 1GHz	
Instrument used	Test Receiver / Spectrum Analyzer	Spectrum Analyzer	
Detector	QP	PK	AV
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 1MHz	RBW: 1MHz VBW: 10Hz or RBW: 1MHz VBW: 270Hz *1)
	20dBc : RBW: 100kHz VBW: 300kHz (S/A)	20dBc : RBW:100kHz/VBW:300kHz	
Test Distance	3m	3m (below 10GHz), 1m*2) (above 10GHz), 0.5m*3) (above 26.5GHz)	

*1) Used for the band edge of the carrier and the harmonics that can be measured. The VBW is based on the inverse of the duty cycle (see Page 32).

*2) Distance Factor: $20 \times \log(3.0m/1.0m) = 9.5dB$

*3) Distance Factor: $20 \times \log(3.0m/0.5m) = 15.6dB$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT without Cradle and EUT on cradle to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Measurement range : 30M-25GHz
Test data : APPENDIX 2
Test result : Pass

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SECTION 7: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	2.5MHz or 3MHz	30kHz	91kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Including enough Duty Cycle	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3MHz or 5MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	1MHz	1MHz	As necessary capture the entire dwell time per hopping channel	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission	Less or equal to 5GHz (Range: 30MHz-25GHz)	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX
Test result : Pass